

<b>Notice of References Cited</b>	Application/Control No. 10/530,030		Applicant(s)/Patent Under Reexamination KANEGAE ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

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*	B	US-6,985,411 B2	01-2006	Kanegae et al.	369/30.04
*	C	US-2006/0110132 A1	05-2006	Takakuwa et al.	386/095
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	K	US-			
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#### NON-PATENT DOCUMENTS

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